# **Power MOSFET**

# 60 V, 21 m $\Omega$ , 27 A, Single N-Channel

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- These Devices are Pb-Free and are RoHS Compliant

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	٧
Gate-to-Source Voltage	9		$V_{GS}$	±20	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	27	Α
Current R <sub>0JC</sub> (Notes 1, 2, 3)	State	T <sub>C</sub> = 100°C		15	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	28	W
R <sub>θJC</sub> (Notes 1, 2)		T <sub>C</sub> = 100°C		9.0	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	9.8	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	State	T <sub>A</sub> = 100°C		6.9	
Power Dissipation	T <sub>A</sub> = 25°C		$P_{D}$	3.8	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.9	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	131	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to + 175	°C
Source Current (Body Diode)			Is	23.5	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 1.1 A)			E <sub>AS</sub>	43	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	5.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

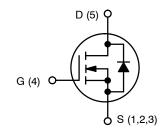
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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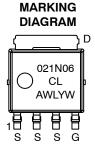
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
60 V	21 mΩ @ 10 V	07.4
00 V	31.5 m $\Omega$ @ 4.5 V	27 A



**N-CHANNEL MOSFET** 



LFPAK4 CASE 760AB



021N06CL = Specific Device Code A = Assembly Location

WL = Wafer Lot
 Y = Year
 W = Work Week

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				28		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25 °C			10	
		V <sub>DS</sub> = 60 V	T <sub>J</sub> = 125°C			250	μA 250
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>G</sub>	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 16 μΑ	1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A		18	21	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 10 A		26	31.5	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> =15 V, I <sub>D</sub>	<sub>)</sub> = 10 A		37		S
CHARGES AND CAPACITANCES	•						•
Input Capacitance	C <sub>ISS</sub>				410		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MH	lz, V <sub>DS</sub> = 25 V		210		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				7.0		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			2.5		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			5.0		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			0.6		
Gate-to-Source Charge	Q <sub>GS</sub>				1.0		nC
Gate-to-Drain Charge	$Q_{GD}$				0.5		1
Plateau Voltage	V <sub>GP</sub>				2.7		V
SWITCHING CHARACTERISTICS (Note 5	)				•	•	•
Turn-On Delay Time	t <sub>d(ON)</sub>				4.0		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V <sub>D</sub>	c = 48 V.		12		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 10 \text{ A}, R_G = 2.5 \Omega$			12		ns
Fall Time	t <sub>f</sub>				1.5		1
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 \text{ V},$ $T_{J} = 25^{\circ}\text{C}$		0.9	1.2		
		I <sub>S</sub> = 10 A	T <sub>J</sub> = 125°C		0.8		_ v
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 10 \text{ A}$			18		
Charge Time	t <sub>a</sub>				9.0		ns
Discharge Time	t <sub>b</sub>				9.0		1
Reverse Recovery Charge	Q <sub>RR</sub>				7.0		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

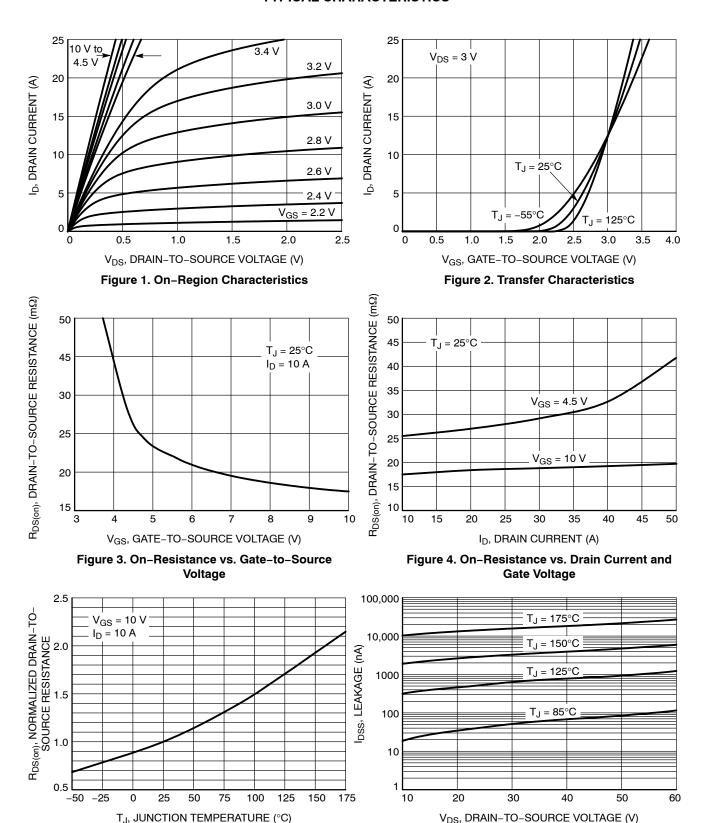
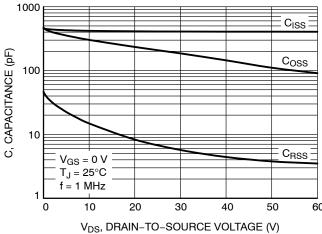


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

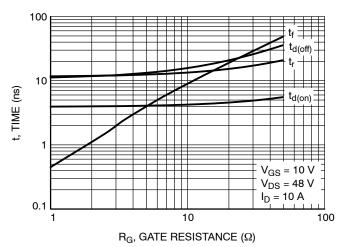


0 60

V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)  $Q_T$ 8 7 6 5 4  $Q_{GS}$  $Q_{GD}$ 3  $V_{DS} = 48 \text{ V}$ 2 T<sub>J</sub> = 25°C  $I_D = 10 A$ 2 Q<sub>G</sub>, TOTAL GATE CHARGE (nC)

Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge



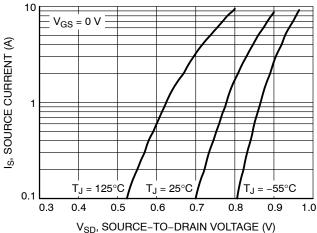
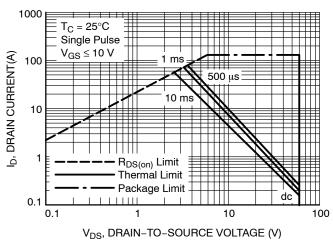


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current



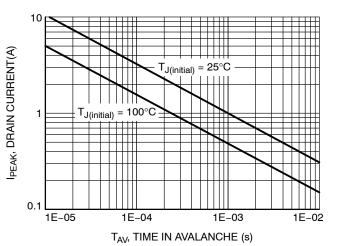


Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Drain Current vs. Time in **Avalanche** 

## **TYPICAL CHARACTERISTICS**

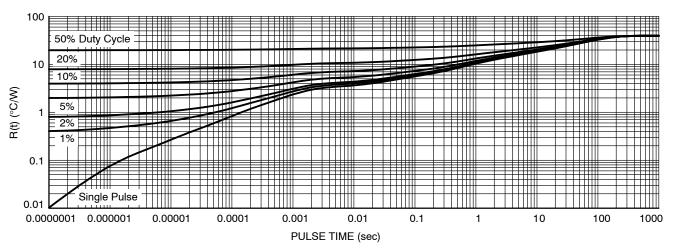


Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMYS021N06CLTWG	021N06CL	LFPAK4 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

# LFPAK4 5x6 CASE 760AB **ISSUE B** Α L1 L2 **♦** 0.25**⋒** A 1/2e SIDE VIEW TOP VIEW 0.10 C DETAIL 'A'

#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

UNIT IN MILLIMETER				
DIM	MIN	NOM	MAX	
Α	1.10	1.20	1.30	
A1	0.00	0.08	0.15	
A2	1.10	1.15	1.20	
А3		0.25		
A4	0.45	0.50	0.55	
b	0.40	0.45	0.50	
b2	3.80	4.10	4.40	
b3	2.00	2.10	2.20	
b4	0.70	0.80	0.90	
b5	0.55	0.65	0.75	
С	0.19	0.22	0.25	
c2	0.19	0.22	0.25	
D	4.05	4.15	4.25	
D1	3.80	4.00	4.20	
D2	3.00	3.10	3.20	
D3	0.30	0.40	0.50	
П	4.80	4.90	5.00	
Ε1	3.10	3.20	3.30	
E2	5.00	5.15	5.30	
е	1.27 BSC			
H L	6.00	6.15	6.30	
L	0.40	0.65	0.85	
L1	0.80	0.90	1.00	
L2	0.80	1.05	1.30	
q	0°	4°	8°	

	SCALE: 2:1	
D1 D2 D3 D3 D3 BOTTOM VIEW		1.300 1.300 1.610 1.610 1.600 0.700 1.150 1.060 1.150 1.270 RECOMMENDED MOUNTING FOOTPRINT

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